Docket No.

210136US99

D STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

RAVINDRANATH DROOPAD ET AL

SERIAL NO:

09/901,109

GAU:

2815

FILED:

JULY 10, 2001

EXAMINER: BAUMEISTER

FOR:

STRUCTURE AND METHOD FOR FABRICATING SEMICONDUCTOR STRUCTURES AND DEVICES UTILIZING THE FORMATION OF A COMPLIANT SUBSTRATE COMPRISING AN OXYGEN-DOPED

COMPOUND SEMICONDUCTOR LAYER

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

05/09/2003 SZEWDIE1 00000047 09901109

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180.00 pp

Respectfully submitted,

OBLON, SPIVAK, McCLFLLAND, MAIER & NEUSTADT, P.O

Richard L. Treanor

Registration No. 36,379

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 03/02)

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				APPLICANT				
LIST OF REFERENCES CITED BY APPLICANT			Ravindranath DROOPAD, et al.					
				FILING DATE		GROUP		
				July 10, 2001		2815		
	U.S. PATENT DOCUMENTS							
EXAMINER INITIAL				NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	UT	5,528,209	06/18/96	Macdonald et al.				
	UV	5,998,781	12/07/99	Vawter et al.				
	UW	6,110,813	08/29/00	Ota et al.				
	UX	6,452,232 B1	09/17/02	Adan				
	UY	6,049,110	04/11/00	Koh				
	UZ	5,559,368	09/24/96	Hu et al.				
	VA	6,392,253 B1	05/21/02	Saxena				
	VB	5,585,288	12/17/96	Davis et al.				
	vc	5,268,327	12/07/93	Vernon				
	VD	6,198,119 B1	03/06/01	Nabatame et al.				
	VE	6,113,225	09/05/00	Miyata et al.				
	VF	5,262,659	11/16/93	Grudkowski et al.				
	VG	6,239,012 B1	05/29/01	Kinsman				
	VH	6,297,598	10/02/01	Wang et al.				
	VI	2002/140012	10/03/02	Droopad				
	VJ	4,866,489	09/12/89	Yokogawa et al.				
	VK	6,080,378	06/27/00	Yokota et al.				
-	VL	5,508,554	04/16/96	Takatani et al.				
	VM	6,477,285 B1	11/05/02	Shanley				
	VN	4,695,120	09/22/87	Holder				
	VO	5,882,948	03/16/99	Jewell				
	VP	5,574,589	11/12/96	Feuer et al.				
	VQ	5,510,665	04/23/96	Conley				
	VR	4,804,866	02/14/89	Akiyama				
	vs	5,057,694	10/15/91	ldaka et al.				
	VT	5,635,453	06/03/97	Pique et al.				
	VU	5,719,417	02/17/98	Roeder et al.				
	W	5,998,819	12/07/99	Yokoyama et al.				
Examiner		<u>'</u>			Date Con	sidered		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	w	2002/0079576	06/27/02	Seshan				
	VX	5,148,504	09/15/92	Levi et al.				
	VY	2002/0195610 A1	12/26/02	Klosowiak				
	VZ	5,477,363	12/19/95	Matsuda				
	WA	5,905,571	05/18/99	Butler et al.				
	WB	5,570,226	10/29/96	Ota				
	wc	5,087,829	02/11/92	Ishibashi et al.				
	WD	2001/0020278 A1	09/06/01	Saito				
	WE	6,496,469 B1	12/17/02	Uchizaki				
	WF	5,679,947	10/21/97	Doi et al.				
	WG	2001/0036142 A1	11/01/01	Kadowaki et al.				
	WH	5,446,719	08/29/95	Yoshida et al.				
	WI	5,831,960	11/03/98	Jiang et al.			<u>-</u>	
	WJ	5,693,140	12/02/97	McKee et al.				
	WK	6,376,337 B1	04/23/02	Wang et al.				
	WL	4,177,094	12/04/79	Kroon		· · ·		
	WM	5,216,359	06/01/93	Makki et al.			·	
	WN	6,307,996 B1	10/23/01	Nashimoto et al.				
	wo	5,371,621	12/06/94	Stevens		<u> </u>		
	WP	2002/0145168 A1	10/10/02	Bojarczuk, Jr et al.			···	
	WQ	3,617,951	11/02/71	Anderson				
	WR	5,838,053	11/17/98	Bevan et al.				
	ws	5,684,302	11/04/97	Wersing et al.				
	WT	5,959,308	09/28/99	Shichijo et al.		-	· · · · · · · · · · · · · · · · · · ·	
	WU	5,362,972	11/08/94	Yazawa et al.				
	WV	5,864,171	01/26/99	Yamamoto et al.				
	ww	5,028,563	07/02/91	Feit et al.				
	WX	5,937,115	08/10/99	Domash				
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	WY	5,878,175	03/02/99	Sonoda et al.	<u> </u>			
	WZ	4,801,184	01/31/89	Revelli				
	XA	5,140,387	08/18/92	Okazaki et al.				
	XB	5,410,622	04/25/95	Okada et al.				
	хс	6,064,783	05/16/00	Congdon et al.				
)	XD	5,772,758	06/30/98	Collins et al.				
	ΧE	5,666,376	09/09/97	Cheng				
	XF	5,976,953	11/02/99	Zavracky et al.				
	XG	5,578,162	11/26/96	D'Asaro et al.				
	XH	5,585,167	12/17/96	Satoh et al.				
	ΧI	5,674,813	10/07/97	Nakamura et al.				
	XJ	5,574,296	11/12/96	Park et al.				
	XK	6,504,189	01/07/03	Matsuda et al.				
	XL	5,987,196	11/16/99	Noble				
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FOREIGN PATENT DOCUMENTS

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	DOCUMENT NUMBER	DATE	COUNTRY	TRANS	LATION NO				
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CBD	EP 0 860 913	08/26/95	EUROPE						
CBE	5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT						
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СВО	WO 02/08806	01/31/02	WIPO						
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CBQ	62-245205	10/26/87	JAPAN W/ENGLISH ABSTRACT		<u> </u>				
CBR	0 600 658	06/08/94	EUROPE						
CBS	0 412 002	02/06/91	EUROPE						
СВТ	2000-349278	12/15/00	JAPAN (ENGLISH ABSTRACT)						
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CBV	0 619 283	10/12/94	EUROPE						
CBW	0 661 561	07/05/95	EUROPE						
CBX	0 331 338	09/06/89	EUROPE						
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